SUPPLEMENTAL AMENDMENT
USSN 10/032,098
ATTORNEY DOCKET NO. Q67557

IN THE CLAIMS

1. (currently amended) An electrical circuit inspection apparatus comprising:

a first inspection functionality operative to sense reflectivity of a conductor location on an electrical circuit to obtain first attribute information with respect to ~~a~~ said conductor location ~~on an electrical circuit~~;

a second inspection functionality operative to sense luminescence at said conductor location to obtain second attribute information with respect to said conductor location ~~on said electrical circuit~~; and

a conductor defect analyzer receiving said first attribute information and said second attribute information, and evaluating a combination of said first attribute information and said second attribute information to determine the presence of a conductor defect at said conductor location, said conductor defect being indicated in said first attribute information, and further indicated in said second attribute information.

2. (canceled)

3. (currently amended) The electrical circuit inspection apparatus according to claim ~~2~~1, wherein said first inspection functionality determines a top width dimension of said conductor based on said sensed reflectivity.

4. (canceled)

5. (currently amended) The electrical circuit inspection apparatus according to claim 43, wherein said second inspection functionality determines a bottom width dimension of said conductor based on said sensed luminescence.

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Claims 6. – 8. (canceled)

9. (currently amended) The electrical circuit inspection apparatus according claim ~~7~~5, wherein said ~~attribute~~ conductor defect analyzer comprises an impedance analyzer receiving said top width dimension and said bottom width dimension for a plurality of conductor locations, and ~~determining~~ determines therefrom an impedance attribute of said conductor.

10. (currently amended) An electrical circuit inspection method comprising:

sensing a reflectivity value ~~obtaining first attribute information~~ for each of a plurality of conductor locations on an electrical circuit to obtain first attribute information for said conductor locations;

sensing a luminescence value to ~~obtaining~~ obtain second attribute information ~~of~~ for said ~~plurality of~~ conductor locations; and

determining a conductor defect at one or more of said conductor locations based on a combination of said first attribute information and said second attribute information, said conductor defect being indicated in said first attribute information and further indicated in said second attribute information.

11. (canceled)

12. (currently amended) The electrical circuit inspection method according to claim ~~11~~10, wherein ~~said~~ obtaining said first attribute information ~~further~~ comprises: ~~receiving said reflectivity value, for said one or more conductor locations; and~~ determining ~~therefrom~~ a top width dimension of said conductor from sensed reflectivity values.

13. (canceled)

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14. (currently amended) The electrical circuit inspection method according to claim ~~13~~12, wherein ~~said~~ obtaining said second attribute information ~~further~~ comprises: ~~receiving said luminescence value for said one or more conductor locations; and~~ determining ~~therefrom~~ a bottom width dimension of said conductor from sensed luminescence values.

Claims 15. - 18 (canceled)

19. (currently amended) The electrical circuit inspection method according to claim ~~16~~14, further comprising determining~~, as said inspection attribute,~~ a cross section configuration of said conductor based on said top width dimension and said bottom width dimension.

20. (currently amended) The electrical circuit inspection method according claim ~~16~~14, further comprising determining~~, as said inspection attribute,~~ an impedance attribute of said conductor, based on said top width dimension and said bottom width dimension for ~~said~~ one or more conductor locations.

Claims 21. - 33. (Canceled)